

Special Issue

Microelectronics Reliability

Message from the Guest Editors

The goal of this Special Issue of *Electronics* is to present state-of-the-art investigations on various reliability technologies and cover all levels of integrated systems and manufacturing:

- materials and processes;
- technologies (CMOS, BiCMOS, etc.);
- transistors;
- components (SRAM, DRAM, sensors, power electronics, etc.);
- integrated circuits (processors, controllers, etc.);
- integrated systems (communication, graphic module, etc.); and packages.

Topics of interest on reliability include, but are not limited to:

- traditional reliability topics (TDDDB, HCT, EM, etc.);
- life testing;
- accelerated testing;
- maintainability;
- failure mechanisms;
- case studies of physical failures;
- mitigation (proactive and passive);
- reliability models;
- stress mechanisms;
- interconnection issues;
- reliability due to radiation effects;
- telemetry, on-die sensors, and instant health monitoring for fast reliability loops.

Guest Editors

Prof. Dr. Sanghyeon Baeg

Electronics Engineering, Hanyang University, Ansan, Korea

Dr. Shi-Jie Wen

Cisco System Inc., USA

Deadline for manuscript submissions

closed (30 November 2021)



Electronics

an Open Access Journal
by MDPI

Impact Factor 2.6
CiteScore 5.3



mdpi.com/si/63749

Electronics

MDPI, Grosspeteranlage 5

4052 Basel, Switzerland

Tel: +41 61 683 77 34

electronics@mdpi.com

[mdpi.com/journal/
electronics](https://mdpi.com/journal/electronics)





Electronics

an Open Access Journal
by MDPI

Impact Factor 2.6
CiteScore 5.3



[mdpi.com/journal/
electronics](https://mdpi.com/journal/electronics)



About the Journal

Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

Editor-in-Chief

Prof. Dr. Flavio Canavero

Department of Electronics and Telecommunications, Politecnico di
Torino, 10129 Torino, Italy

Author Benefits

High Visibility:

indexed within Scopus, SCIE (Web of Science), CAPlus /
SciFinder, Inspec, Ei Compendex and other databases.

Journal Rank:

JCR - Q2 (Physics, Applied) / CiteScore - Q2 (Control and
Systems Engineering)

Rapid Publication:

manuscripts are peer-reviewed and a first decision is
provided to authors approximately 16.4 days after
submission; acceptance to publication is undertaken in 2.4
days (median values for papers published in this journal in
the second half of 2024).